•								RE	EVISI	ONS										
LTR					D	ESCR:	[PTIC	N				•	D	ATE	(YR-MO	-DA)		APPR	OVED	
																		·		
211 A. A. A.																				
+ 1 .	e de Editor																			į
·																				
REV																				
SHEET																				
REV																				
SHEET													·							
REV STATU	JS		<u> </u>	RE	v	•														
OF SHEETS					EET		1	2	3	4	5	6	7	8	9	10	11	12		
		,			ARED E	BY		-						<u> </u>						
PMIC N/A						uncan				DI	EFENS				S SU HIO		CENT	ľER		
STAND)	CHEC	KED BY	·							ALIC	, O		454			<u> </u>	
MIL	ITAF WIN				ael Jo															
DRA	7M T IV	G		APPR	OVED E	BY				MIC	ROC	IRC	JIT,	LI	NEAR	, 5	VOI	т, 1	DUAI	
THIS DRAWING FOR USE BY A	G IS A	VAILA	BLE	Kend	all A.	Cotto	ngim			CHI	NNE	L, I	DC/D	C C	ONVE	RTE	R, H	YBR:	ID	
AND AGEN	CIES O	F THE		DRAW		PROVAL	DATE													
	- · ·	3			94-05	-20				SIZ	E	CAG	E CO	DE		59	62-	9319	91	
AMSC N/A				REVI	SION L	EVEL.				A		6	726	8	L.,					
,										SHE	ET		1		OF		12			
DESC FORM 107																				

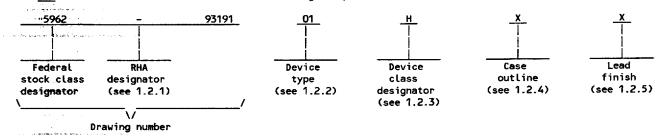
JUL 91

<u>DISTRIBUTION STATEMENT A.</u> Approved for public release; distribution is unlimited.

5962-E312-93

1	SCOPE

- 1.1 <u>Scope</u>. This drawing forms a part of a one part one part number documentation system (see 6.6 herein). This drawing describes device requirements for hybrid microcircuits to be processed in accordance with MIL-H-38534. Two product assurance classes, military high reliability (device class H) and space application (device class K) and a choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of radiation hardness assurance levels are reflected in the PIN.
 - 1.2 PIN. The PIN shall be as shown in the following example:



- 1.2.1 <u>Radiation hardness assurance (RHA) designator</u>. Device classes H and K RHA marked devices shall meet the MIL-H-38534 specified RHA levels and shall be marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.
 - 1.2.2 Device type(s). The device type(s) shall identify the circuit function as follows:

Device type	Generic number	<u>Circuit function</u>
. 01	MFL2805D	DC-DC Converter, 50 W, 5 V output

1.2.3 <u>Device class designator</u>. This device class designator shall be a single letter identifying the product assurance level as follows:

Device class

Device requirements documentation

H or K

Certification and qualification to MIL-H-38534

1.2.4 Case outline(s). The case outline(s) shall be as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	<u>Terminals</u>	<u>Package style</u>
X	See figure 1	12	Flange mount

1.2.5 <u>Lead finish</u>. The lead finish shall be as specified in MIL-H-38534 for classes H and K. Finish letter "X" shall not be marked on the microcircuit or its packaging. The "X" designation is for use in specifications when lead finishes A, B, and C are considered acceptable and interchangeable without preference.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	SIZE A		5962-93191
DAYTON, OHIO 45444		REVISION LEVEL	SHEET 2

1.3 <u>Absolute maximum ratings</u> . <u>1</u> /	
Input voltage range	5 V dc to +50 V dc 18 W +300°C -65°C to +150°C
1.4 Recommended operating conditions.	
Input voltage range	+16 V dc to +40 V dc ≤ 50 W -55°C to +125°C
2. APPLICABLE DOCUMENTS	
2.1 Government specification, standards, and handbook. Unless standards, and handbook of the issue listed in that issue of the Standards specified in the solicitation, form a part of this description. SPECIFICATION	ne Department of Defense Index of Specifications and
MILITARY	
MIL-H-38534 - Hybrid Microcircuits, General Specificat	tion for.
STANDARDS	
MILITARY	
MIL-STD-480 - Configuration Control-Engineering Change MIL-STD-883 - Test Methods and Procedures for Microele MIL-STD-1835 - Microcircuit Case Outlines.	
HANDBOOK	
MILITARY	

MIL-HDBK-780 - Standardized Military Drawings.

(Copies of the specification, standards, and handbook required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	SIZE A		5962-93191
DAYTON, OHIO 45444		REVISION LEVEL	SHEET 3

DESC FORM 193A JUL 91

9004708 0006853 547

^{1/} Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

3. REQUIREMENTS

- 3.1 Item requirements. The individual item requirements shall be in accordance with MIL-H-38534 and as specified herein.
- 3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-H-38534 and herein.
 - 3.2.1 <u>Case outline(s)</u>. The case outline(s) shall be in accordance with 1.2.4 herein and figure 1.
 - 3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.
- 3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.
- 3.5 <u>Marking</u>. Marking shall be in accordance with MIL-H-38534. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in QML-38534.
- 3.6 <u>Manufacturer eligibility</u>. In addition to the general requirements of MIL-H-38534, the manufacturer of the part described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, produced on the certified line, for each device type listed herein. The data should also include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DESC-EC) upon request.
- 3.7 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance submitted to DESC-EC shall affirm that the manufacturer's product meets the requirements of MIL-H-38534 and the requirements herein.
- 3.8 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-H-38534 shall be provided with each lot of microcircuits delivered to this drawing.
 - 4. QUALITY ASSURANCE PROVISIONS
 - 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-H-38534.
 - 4.2 <u>Screening</u>. Screening shall be in accordance with MIL-H-38534. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DESC-EC or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
 - (2) T_A as specified in accordance with table I of method 1015 of MIL-STD-883.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-93191
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	SHEET 4

Test	Symbol	Conditions $-55^{\circ}C \leq T_{C} \leq +125^{\circ}C$	Group A subgroups	Device type	Limits		Unit
	 	-55° C ≤ T _C ≤ +125°C $V_{IN} = 28 \text{ V dc} \pm .5 \text{ V dc}$ no external sync, C _L = 0 unless otherwise specifie	d		 Min	 Max	
Output voltage	V _{OUT}	 I _{OUT} = ±5.0 A dc, (main)	11	01	+4.95	+5.05	5 V
			2,3	-	+4.85	+5.15	<u> </u>
		I _{OUT} = ±5.0 A dc, (dual)	1	-	-4.92	-5.08	3
			2,3		-4.82	-5.18	B
Output current 1/	I _{OUT}	 V _{IN} = 16 V, 28 V, and 40 V dc, sum of both outputs	1,2,3	01	0.0	10.0	A
Output ripple voltage	V _{RIP}	 I _{OUT} = ±5.0 A, (main) BW = 10 kHz to 2 MHz	11	_ 01		50	mV p-p
		BW = 10 kHz to 2 MHz	2,3	_		100	
		 I _{OUT} = ±5.0 A, (dual) BW = 10 kHz to 2 MHz	11	-		50	
	ļ	BW = 1U KHZ to 2 MHZ	2,3			100	
Line regulation	VR LINE	I _{OUT} = ±5.0 A, (main) V _{IN} = 16 V dc to 40 V dc	1,2,3	01		50	mV
		I _{OUT} = ±5.0 A, (dual) V _{IN} = 16 V dc to 40 V dc				100	
Load regulation	VRLOAD	I _{OUT} = 0 to ±5.0 A, (main)	1,2,3	01		50	mV
	!	I _{OUT} = 0 to ±5.0 A, (dual)			 	100	
Input current	IIN	I _{OUT} = 0 A, inhibit 1 (pin 4) = 0	1,2,3	01		14	mA
		I _{OUT} = 0 A, inhibit 2 (pin 12) = 0				70	
		I _{OUT} = 0 A, inhibit 1 (pin 4) = open and inhibit 2 (pin 12) = open				120	
Input ripple current	IRIP	 I _{OUT} = ±5.0 A, BW = 10 kHz to 10 MHz	11	_ 01		45	mA p-p
		BW = 10 kHz to 10 MHz	2,3	<u> </u>	1	50	
Efficiency	Efficiency Eff I _{OUT} = ±5.0 A		1	_ 01	77		%
	4.11		2,3	1	75		
See footnotes at end o	table.					,	
STANDARDIZED MILITARY DRAWING		SIZE A				5962-931	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444				REVIS	ION LEV	EL	SHEET 5

DESC FORM 193A JUL 91

: **= 9**004708 0006855 31T **=**

Test	Symbol Conditions -55°C ≤ T _C ≤ +125°C		Group A subgroups	Device type	Limits		Unit
		V _{IN} = 28 V dc ± .5 V dc no external sync, C _L = unless otherwise specifie	0 d		 Min	Max	
Isolation	 ISO 	 Input to output or any pin to case at 500 V dc	1	01	100		MΩ
Capacitive load 2/3/ (each output)	c _L	 No effect on dc performanc	e 4	01		500	μF
Power dissipation load fault	 P _D	 Short circuit 	11	_ 01		16	_ w
and the second section of the second section of the second section of the second section secti	<u> </u>	<u> </u>	2,3		İ L	18	
Switching frequency	 F _S	 I _{OUT} = ±5.0 A	4,5,6	 01 	525	675	 kHz
External sync range 4/	FSYNC	 I _{OUT} = ±5.0 A, TTL level to pin 6	4,5,6	 01 	525	675	kHz
Output response to step transient load changes <u>5</u> /	1	 50 percent load to/from 100 percent load	4,5,6	01	 -350 	+350	mV pk
Recovery time step transient load changes <u>3/5/6</u> /	TTLOAD		4,5,6	01		3.0	ms
Output response to transient step line changes 3/7/	VTLINE	I _{OUT} = ±5.0 A, Input step from 16 V dc to 40 V dc	4,5,6	01	 -300 	+300	 mV pk
	-	 I _{OUT} = ±5.0 A, Input step from 40 V dc to 16 V dc			 -300 	 +300 	
Recovery time, transient step line changes <u>3</u> / <u>6</u> /	TTLINE	 1 _{OUT} = ±5.0 A, Input step from 16 V dc to 40 V dc	4,5,6	01		300	μs
		 I _{OUT} = ±5.0 A, Input step from 40 V dc to 16 V dc	* * *		 	300	
Turn-on overshoot <u>3</u> /	Vtonos	 I _{OUT} = ±5.0 A, V _{IN} = 0 to <u>28 V dc</u>	4,5,6	01		±25	mV pk
Turn-on delay time <u>8</u> /	 Ton _D	 I _{OUT} = ±5.0 A, V _{IN} = 0 to 28 V dc	4,5,6	01	 	6	ms
Load fault recovery <u>3</u> /	Tr _{LF}	I _{OUT} = ±5.0 A	4,5,6	01	 	4	ms
See footnotes at top of	next page	-					
STANDARDIZED MILITARY DRAWING		SIZE			5	962-9319	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444				REVISI	ON LEVE	L SH	EET

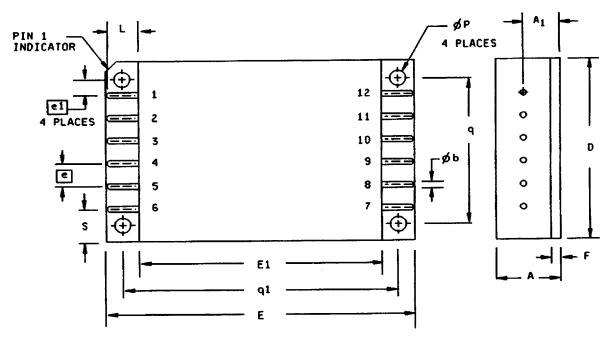
TABLE I. <u>Electrical performance characteristics</u> - Continued.

- 1/ The output power available from either output is limited to 35 watts (i.e. 70 percent of the total output power).
- 2/ Capacitive load may be any value from 0 to the maximum limit without compromising dc performance.
- 2/ Parameter shall be tested as part of design characterization and after design or process changes; therefore, the Parameter shall be guaranteed to limits specified in table I.
- $\frac{4}{4}$ A TTL level waveform (V_{IH} = 4.5 V minimum, V_{IL} = 0.8 V maximum) with a 50 percent ±10 percent duty cycle applied to the sync input pin (pin 6) within the the sync range frequency shall cause the converter's switching frequency to become synchronous with the frequency applied to the sync input pin (pin 6).
- $\underline{5}$ / Load step transition time is 10 microseconds maximum.
- $\underline{6}$ / Recovery time is measured from the initiation of the transient until V_{OUT} has returned to within ± 1 percent of its final value.
- $\underline{7}$ / Input step transition time greater than 10 microseconds.
- $\underline{8}$ / Turn-on delay time measurement is either for a step application of power at the input or the removal of a ground signal from the inhibit 1 pin (pin 4) or inhibit 2 pin (pin 12) while power is applied to the input

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	SIZE A		5962-93191
DAYTON, OHIO 45444		REVISION LEVEL	SHEET 7

DESC FORM 193A JUL 91

9004708 0006857 192



Symbol	Mill	imeters	<u>Inches</u>		
•	Min	Max	Min	Max	
A	Î .	10.16		.400	
A1	5.46	5.72	.215	.225	
φb	.89	1.14	.035	.045	
D	37.97	38.23	1.495	1.505	
e	5.08	BSC	.200 BSC		
e1	3.30	BSC	.130 BSC		
E	75.95	76.33	2.990	3.005	
E1	63.37	63.63	2.495	2.505	
F	1.14	1.40	.045	.055	
L	6.10	6.60	.240	.260	
ФР	3.12	3.38	.123	.133	
q	31.88	32.13	1.255	1.265	
q1	69.57	69.82	2.739	2.749	
s	6.22	6.48	.245	.255	

NOTES:

- The case outline X was originally designed using inch-pound units of measurement, in the event of conflict between the metric and inch-pound units, the inch-pound shall take precedence.
- 2. Device weight: 86 grams maximum.

FIGURE 1. Case outline.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-93191
		REVISION LEVEL	SHEET 8

DESC FORM 193A JUL 91

== 9004708 0006858 029 **==**

Device type	01		
Case outline	х		
Terminal number	Terminal symbol		
1	Input		
2	Input common		
3	Tri		
4	Inhibit 1		
5	Sync output		
6	Sync input		
7	Positive output		
8	Output common		
9	Negative output		
10	No connection		
11	Slave to master		
12	Master to slave/ inhibit 2		

NOTES:

- 1. Multiple devices may be used in parallel to drive a common load. When using this mode of operation the load current is sharred by two or three devices. In the current sharing mode, one device is designated as the master. The slave to master pin (pin 11) of the master device is not connected and the master to slave/inhibit pin (pin 12) of the master is connected to the slave to master pin (pin 11) of the slave device(s). The device(s) designated as slave(s) have the master to slave/inhibit 2 pin (pin 11) connected to the output common pin (pin 8).
- 2. A second slave device may be placed in parallel with a master and slave device, this requires the Tri pin (pin 3) of the master device to be connected to the output common pin (pin 8). When paralleled, 95 percent of the sum of the power of the devices is available at the load. This means that 185 watts at 15 volts is available for three devices in parallel.
- 3. The device has a sync input pin (pin 6) and a sync output pin (pin 5) which allows multiple devices, whether their in a single unit or master/slave configurations to be synchronized to a system clock or each other. Two or more devices may be synchronized to each other by connecting the sync output pin (pin 5) of one to the sync input pin (pin 6) of another.
- 4. The device has two inhibit options, one is ground referenced to the input common and the other is referenced to the output common. The output referred inhibit pin uses the master to slave/inhibit 2 pin (pin 12). This pin is normally used to parallel devices, and a TTL compatiable open collector low will inhibit the device when applied to this pin.

FIGURE 2. Terminal connections.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-93191
		REVISION LEVEL	SHEET 9

DESC FORM 193A JUL 91

■ 9004708 0006859 T65 ■

TABLE II. Electrical test requirements.

A STATE OF STATE		1
	MIL-H-38534 test requirements	Subgroups (in accordance with MIL-H-38534, group A test table)
The second secon	Interim electrical parameters	
	Final electrical test parameters	1*, 2, 3, 4, 5, 6
e and market and the second of	Group A test requirements	1, 2, 3, 4, 5, 6
The second of th	Group C end-point electrical parameters	1
	MIL-STD-883, group E end-point electrical parameters for RHA devices	Subgroups ** (in accordance with method 5005, group A test table)
and the second second section of the second section is a second section of the second section of the second section se	\$ m.	İ

^{*} PDA applies to subgroup 1.

- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with MIL-H-38534 and as specified herein.
 - 4.3.1 Group A inspection. Group A inspection shall be in accordance with MIL-H-38534 and as follows:
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 7, 8, 9, 10, and 11 shall be omitted.
 - 4.3.2 Group B inspection. Group B inspection shall be in accordance with MIL-H-38534.
 - 4.3.3 Group C inspection. Group C inspection shall be in accordance with MIL-H-38534 and as follows:
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DESC-EC or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
 - (2) T_A as specified in accordance with table I of method 1005 of MIL-STD-883.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
 - 4.3.4 Group D inspection. Group D inspection shall be in accordance with MIL-H-38534.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-93191
		REVISION LEVEL	SHEET 10

DESC FORM 193A JUL 91

9004708 0006860 787

^{**} When applicable to this standardized military drawing, the subgroups shall be defined.

- 4.3.5 <u>Group E inspection</u>. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein). RHA levels for device classes H and K shall be M, D, R, and H. RHA quality conformance inspection sample tests shall be performed at the RHA level specified in the acquisition document.
 - a. RHA tests for device classes H and K for levels M, D, R, and H shall be performed through each level to determine at what levels the devices meet the RHA requirements. These RHA tests shall be performed for initial qualification and after design or process changes which may affect the RHA performance of the device.
 - b. End-point electrical parameters shall be as specified in table II herein.
 - c. Prior to total dose irradiation, each selected sample shall be assembled in its qualified package. It shall pass the specified group A electrical parameters in table I for subgroups specified in table II herein.
 - d. For device classes H and K, the devices shall be subjected to radiation hardness assured tests as specified in MIL-H-38534 for RHA level being tested, and meet the postirradiation end-point electrical parameter limits as defined in table I at T_A = +25°C ±5 percent, after exposure.
 - e. Prior to and during total dose irradiation testing, the devices shall be biased to establish a worst case condition as specified in the radiation exposure circuit.
 - f. For device classes H and K, subgroups 1 and 2 in table V, method 5005 of MIL-STD-883 shall be tested as appropriate for device construction.
 - g. When specified in the purchase order or contract, a copy of the RHA delta limits shall be supplied.
 - PACKAGING
 - 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-H-38534.
 - 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).
- 6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DESC-EC, telephone (513) 296-6047.
- 6.5 <u>Comments</u>. Comments on this drawing should be directed to DESC-EC, Dayton, Ohio 45444, or telephone (513) 296-5373.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-93191
		REVISION LEVEL	SHEET 11

6.6 One part — one part number system. The one part — one part number system described below has been developed to allow for transitions between identical generic devices covered by the three major microcircuit requirements documents (MIL-H-38534, MIL-I-38535, and 1.2.1 of MIL-STD-883) without the necessity for the generation of unique PIN's. The three military requirements documents represent different class levels, and previously when a device manufacturer upgraded military product from one class level to another, the benefits of the upgraded product were unavailable to the Original Equipment Manufacturer (OEM), that was contractually locked into the original unique PIN. By establishing a one part number system covering all three documents, the OEM can acquire to the highest class level available for a given generic device to meet system needs without modifying the original contract parts selection criteria.

Military documentation format	Example PIN under new system	Manufacturing source listing	Document <u>Listing</u>
New MIL-H-38534 Standardized Military Drawings	5962-XXXXXZZ(H or K)YY	QML-38534	MIL-BUL-103
New MIL-I-38535 Standardized Military Drawings	5962-XXXXXZZ(Q or V)YY	QML-38535	MIL-BUL-103
New 1.2.1 of MIL-STD-883 Standardized Military Drawings	5962-XXXXXZZ(M)YY	MIL-BUL-103	MIL-BUL-103

6.7 <u>Sources of supply for device classes H and K</u>. Sources of supply for device classes H and K are listed in QML-38534. The vendors listed in QML-38534 have submitted a certificate of compliance (see 3.7 herein) to DESC-EC and have agreed to this drawing.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-93191
		REVISION LEVEL	SHEET 12

DESC FORM 193A JUL 91

■ 9004708 0006862 55T **■**

43016